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IN THE U.S. PATENT AND TRADEMARK OFFICE

April 14, 2006

Applicants : Atsushi YABE et al  
For : ELECTROLESS COPPER PLATING SOLUTION  
PCT International Application No.: PCT/JP2004/011327  
PCT International Filing Date: July 30, 2004  
U.S. Application No.  
(if known, see 37 CFR 1.5): Unknown  
Atty. Docket No.: 4700.P0327US

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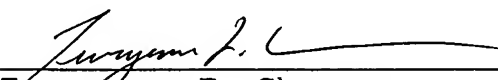
**INFORMATION DISCLOSURE STATEMENT**

Sir:

In compliance with the provisions of Rules 1.97(b)(1) and 1.98, enclosed herewith is a copy of the International Search Report, Form PTO-1449 and the references cited thereon. D1-D4 have been discussed in the specification. D1 and D5-D8 are cited in the International Search Report. D1, D5 and D6 are cited in the International Preliminary Examination Report. These references constitute the art known to the Applicants and are believed to be distinguishable from the claimed invention. Accordingly, further comment at this point in time should not be necessary.

Further consideration is respectfully solicited.

Respectfully submitted,

  
Terryence F. Chapman

TFC/smd

36/376231

IAP20 Reg's of CTR/PTO 14 APR 2006

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Encl: Copy of International Search Report  
Form PTO-1449 and one copy of each listed reference

336.05/03

INFORMATION  
DISCLOSURE  
CITATION

Applicant: Atsushi YABE et al

Ser.No.: Unknown

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Filed: Unknown

Atty. Docket No.: 4700

Date: April 14, 2006

P0327US76231

## U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant
	AA			
	AB			
	AC			
	AD			
	AE			
	AF			
	AG			

## FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Country Code - Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Trans.
	AH	JP 2002-249879	09-06-2002	ITABASHI et al	Abstract
	AI	WO 01/49898 A1	07-12-2001	IMORI et al	Abstract
	AJ	WO 03/091476 A1	11-06-2003	IMORI et al	Abstract
	AK	WO 2004/108986 A1	12-16-2004	IMORI et al	Abstract
	AL	JP 60-245783	12-05-1985	UIRIAMU et al	Abstract
	AM	JP 3-287779	12-18-1991	MIURA et al	Abstract
	AN	WO 01/63016 A1	08-30-2001	GALES et al	
	AO	JP 05-39580	02-19-1993	OTSUKA et al	Abstract

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	(Include Author, Title, Date, Pages, Etc.)
	AP	
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EXAMINER SIGNATURE		DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.